



FCC TEST REPORT

Issued to

Cellon Communications Technology (ShenZhen)Co., Ltd.

For

GSM Mobile Phone

Model Name C7519, HSD1303, TE1303MXHSD1303PE, HSD1303AL, HSD1303CL, HSD1303EC, HSD1303MV, HSD1303OM, HSD1303MX, CL1303
Trade Name CLARO, PCD, CELLON, Telefonica
Brand Name PCD
FCC ID T38PCD7519
Standard 47 CFR Part 15 Subpart B
Test date April 21, 2011 – May 18, 2011
Issue date May 23, 2011

by
Shenzhen Morlab Communications Technology Co., Ltd.

Tested by

Tu Lang
Tu Lang

Date

2011.5.23

Approved by

Shu Luan
Shu Luan

Date

2011.5.23

Review by

Huang Pulong
Huang Pulong

Date

2011.5.23

CTIA Authorized Test Lab

LAB CODE 20081223-00

IEEE 1725

OTA

OFTA

電訊管理局



GCF
Official Observer of
Global Certification Forum

Bluetooth
BQTF

FCC
Reg. No.
741109

The report refers only to the sample tested and does not apply to the bulk. This report is issued in confidence to the client and it will be strictly treated as such by the Shenzhen MORLAB Communication Technology Co., Ltd. It may not be reproduced rather in its entirety or in part and it may not be used for advertising. The client to whom the report is issued may, however, show or send it, or a certified copy thereof prepared by the Shenzhen MORLAB Telecommunication Co., Ltd to his customer. Supplier or others persons directly concerned. Shenzhen MORLAB Telecommunication Co., Ltd will not, without the consent of the client enter into any discussion of correspondence with any third party concerning the contents of the report. In the event of the improper use of the report, Shenzhen MORLAB Telecommunication Co., Ltd reserves the rights to withdraw it and to adopt any other remedies which may be appropriate.

Shenzhen MORLAB Communication Technology Co., Ltd.

3/F, Electronic Testing Building, Shahe Road, Xili, Nanshan District, Shenzhen, 518055 P. R. China

Tel: +86 755 61281201 Fax: +86 755 86130218

TABLE OF CONTENTS

1. GENERAL INFORMATION	3
1.1 EUT Description	3
1.2 Test Standards and Results	4
1.3 Facilities and Accreditations	5
1.3.1 Facilities	5
1.3.2 Test Environment Conditions	5
1.3.3 Measurement Uncertainty	5
2. TEST CONDITIONS SETTING	6
2.1 Test Mode	6
2.2 Test Setup and Equipments List	7
2.2.1 Conducted Emission	7
2.2.2 Radiated Emission	8
3. 47 CFR PART 15B REQUIREMENTS	9
3.1 Conducted Emission	9
3.1.1 Requirement	9
3.1.2 Test Description	9
3.1.3 Test Result	9
3.2 Radiated Emission	11
3.2.1 Requirement	11
3.2.2 Test Description	11
3.2.3 Test Result	11

Change History		
Issue	Date	Reason for change
1.0	May 23, 2011	First edition

1. GENERAL INFORMATION

1.1 EUT Description

EUT Type GSM Mobile Phone
Serial No. (n.a, marked #1 by test site)
Hardware Version C7519_MB_P3
Software Version C7519_5.7S_PCD_DEB
Applicant Cellon Communications Technology(ShenZhen)Co., Ltd.
13/F, Skyworth Building C Gaoxin S. Ave. 1st, High-Tech industrial Park
NanShan, ShenZhen
Manufacturer Cellon Communications Technology(ShenZhen)Co., Ltd.
13/F, Skyworth Building C Gaoxin S. Ave. 1st, High-Tech industrial Park
NanShan, ShenZhen
Modulation Type GPRS/GSM Mode with GMSK Modulation
EDGE Mode with 8PSK Modulation
WCDMA Mode with QPSK Modulation
HSDPA Mode with QPSK Modulation
Power Supply Battery
Model Name: BTR8093
Brand name: PCD
Capacitance: 1200mAh
Rated voltage: 3.7V
Charge Limit: 4.2V
Ancillary Equipment 1 ... AC Adapter (Charger for Battery)
Model Name: ADR2100
Brand Name: PCD
Serial No.: (n.a. marked #1 by test site)
Rated Input: ~ 100-240V, 300mA, 60Hz
Rated Output: = 5V, 650mA

Note 1: The EUT is a GSM Mobile Phone; it supports GSM 850MHz, 900MHz, 1800MHz, 1900MHz, GPRS, EDGE, WCDMA 850MHz, WCDMA 1900MHz and HSDPA module. GSM 850MHz, 1900MHz, GPRS, EDGE, WCDMA 850MHz, 1900MHz, and HSDPA module are tested in this report.

Note 2: The EUT is equipped with a T-Flash card slot; equipped with a special port which can be connected to the ancillary equipments supplied by the manufacturer e.g. the AC Adapter and the USB Adapter Cable.

Note 3: For a more detailed description, please refer to Specification or User's Manual supplied by the applicant and/or manufacturer.

1.2 Test Standards and Results

The objective of the report is to perform testing according to 47 CFR Part 15 Subpart B:

No.	Identity	Document Title
1	47 CFR Part 15 (10-1-09 Edition)	Radio Frequency Devices

Test detailed items/section required by FCC rules and results are as below:

No.	Section	Description	Result
1	15.107	Conducted Emission	PASS
2	15.109	Radiated Emission	PASS

NOTE: The tests were performed according to the method of measurements prescribed in ANSI C63.4 2003.

1.3 Facilities and Accreditations

1.3.1 Facilities

Shenzhen Morlab Communications Technology Co., Ltd. Morlab Laboratory is a testing organization accredited by China National Accreditation Service for Conformity Assessment (CNAS) according to ISO/IEC 17025. The accreditation certificate number is L3572.

All measurement facilities used to collect the measurement data are located at 3/F, Electronic Testing Building, Shahe Road, Xili, Nanshan District, Shenzhen, 518055 P. R. China. The test site is constructed in conformance with the requirements of ANSI C63.7, ANSI C63.4 and CISPR Publication 22; the FCC registration number is 741109.

1.3.2 Test Environment Conditions

During the measurement, the environmental conditions were within the listed ranges:

Temperature (°C):	15 - 35
Relative Humidity (%):	30 -60
Atmospheric Pressure (kPa):	86-106

1.3.3 Measurement Uncertainty

The uncertainty is calculated using the methods suggested in the "Guide to the Expression of Uncertainty in Measurement" (GUM) published by ISO.

Uncertainty of Conducted Emission:	±1.8dB
Uncertainty of Radiated Emission:	±3.1dB

2. TEST CONDITIONS SETTING

2.1 Test Mode

- (1) The first test mode (USB)

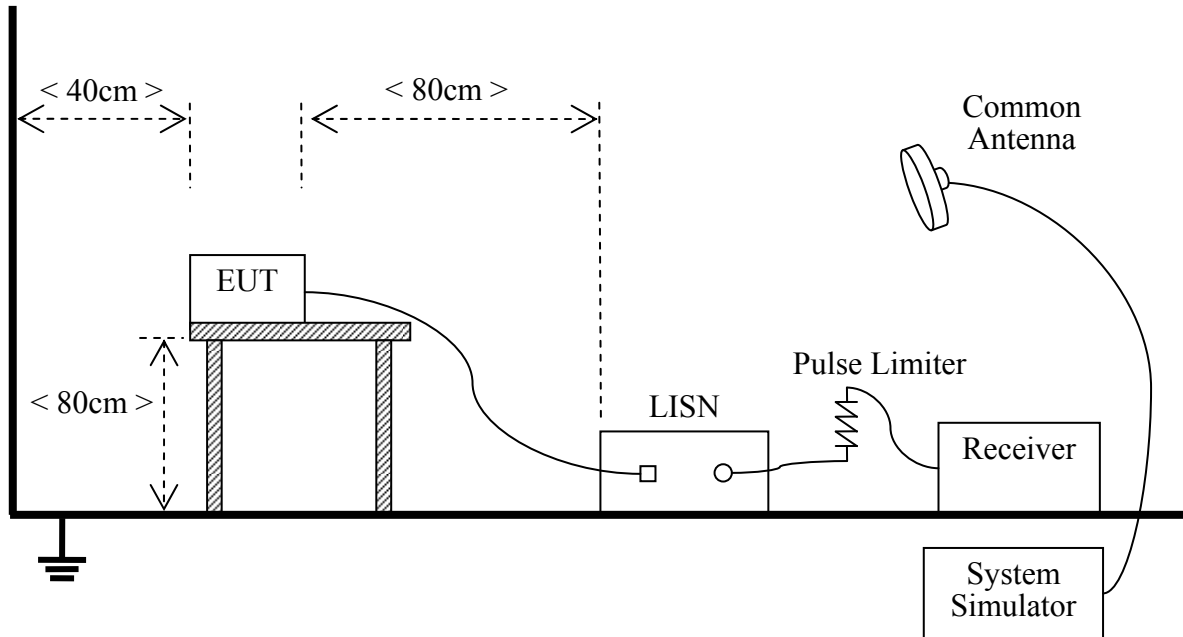
The EUT configuration of the emission tests is TransFlash Card + EUT + Battery + PC.

In this test mode, the EUT with a TransFlash Card embedded is connected with a PC via a special USB cable supplied by applicant. During the measurement, a communication link was established between the EUT and a System Simulator (SS), simultaneity, the data is transmitting between the PC and the TransFlash Card of the EUT.

2.2 Test Setup and Equipments List

2.2.1 Conducted Emission

A. Test Setup:



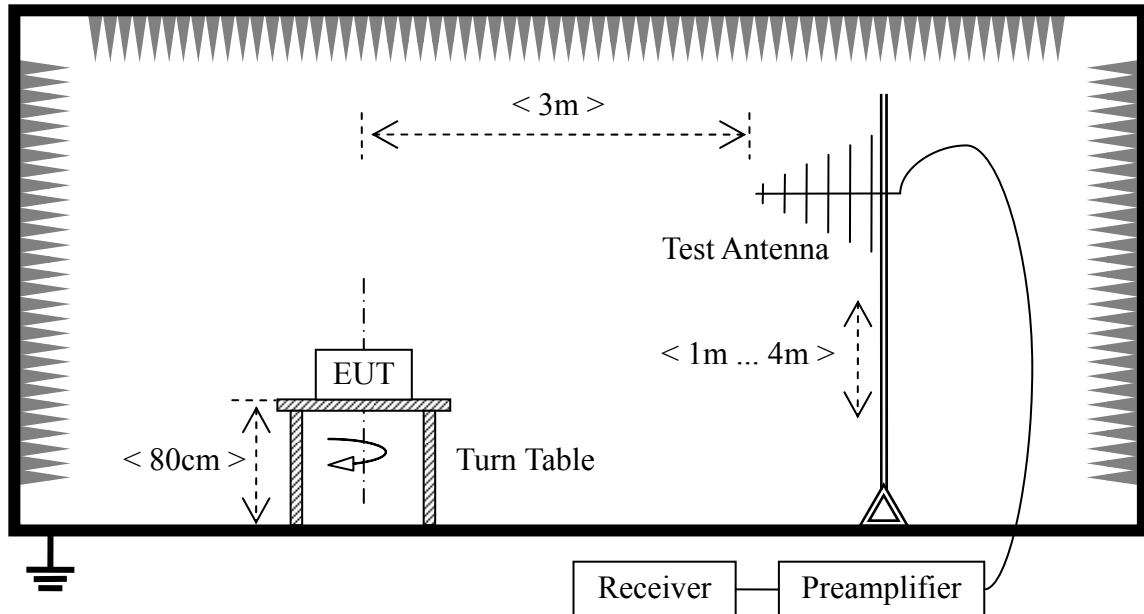
The EUT is placed on a 0.8m high insulating table, which stands on the grounded conducting floor, and keeps 0.4m away from the grounded conducting wall. The EUT is connected to the power mains through a LISN which provides $50\Omega/50\mu\text{H}$ of coupling impedance for the measuring instrument. The Common Antenna is used for the call between the EUT and the System Simulator (SS). A Pulse Limiter is used to protect the measuring instrument. The factors of the whole test system are calibrated to correct the reading.

B. Equipments List:

Description	Manufacturer	Model	Serial No.	Cal. Date
Receiver	Agilent	E7405A	US44210471	2010.09
LISN	Schwarzbeck	NSLK 8127	812744	2010.09
Pulse Limiter (20dB)	Schwarzbeck	VTSD 9561-D	9391	(n.a.)
System Simulator	Agilent	E5515C	GB43130131	2010.09
Personal Computer	IBM	IBM_T20	(n.a.)	(n.a.)
Bluetooth-Headset	Nokia	HS-36W	(n.a.)	(n.a.)
T-Flash Card	SanDisk	256MB	(n.a.)	(n.a.)

2.2.2 Radiated Emission

C. Test Setup:



The test is performed in a 3m Semi-Anechoic Chamber; the antenna factor, cable loss and so on of the site (factors) is calculated to correct the reading. The EUT is placed on a 0.8m high insulating Turn Table, and keeps 3m away from the Test Antenna, which is mounted on a variable-height antenna master tower.

D. Equipments List:

Description	Manufacturer	Model	Serial No.	Cal. Date
Receiver	Agilent	E7405A	US44210471	2010.09
Semi-Anechoic Chamber	Albatross	9m*6m*6m	(n.a.)	2010.09
Test Antenna - Bi-Log	Schwarzbeck	VULB 9163	9163-274	2010.09
Test Antenna - Horn	Schwarzbeck	BBHA 9120C	9120C-384	2010.09
Personal Computer	IBM	IBM_T20	(n.a.)	(n.a.)
Bluetooth-Headset	Nokia	HS-36W	(n.a.)	(n.a.)
T-Flash Card	SanDisk	256MB	(n.a.)	(n.a.)

3. 47 CFR PART 15B REQUIREMENTS

3.1 Conducted Emission

3.1.1 Requirement

According to FCC section 15.107, the radio frequency voltage that is conducted back onto the AC power line on any frequency within the band 150kHz to 30MHz shall not exceed the limits in the following table, as measured using a 50 μ H/50 Ω line impedance stabilization network (LISN).

Frequency range (MHz)	Conducted Limit (dB μ V)	
	Quasi-peak	Average
0.15 - 0.50	66 to 56	56 to 46
0.50 - 5	56	46
5 - 30	60	50

NOTE:

- The limit subjects to the Class B digital device.
- The lower limit shall apply at the band edges.
- The limit decreases linearly with the logarithm of the frequency in the range 0.15 - 0.50MHz.

3.1.2 Test Description

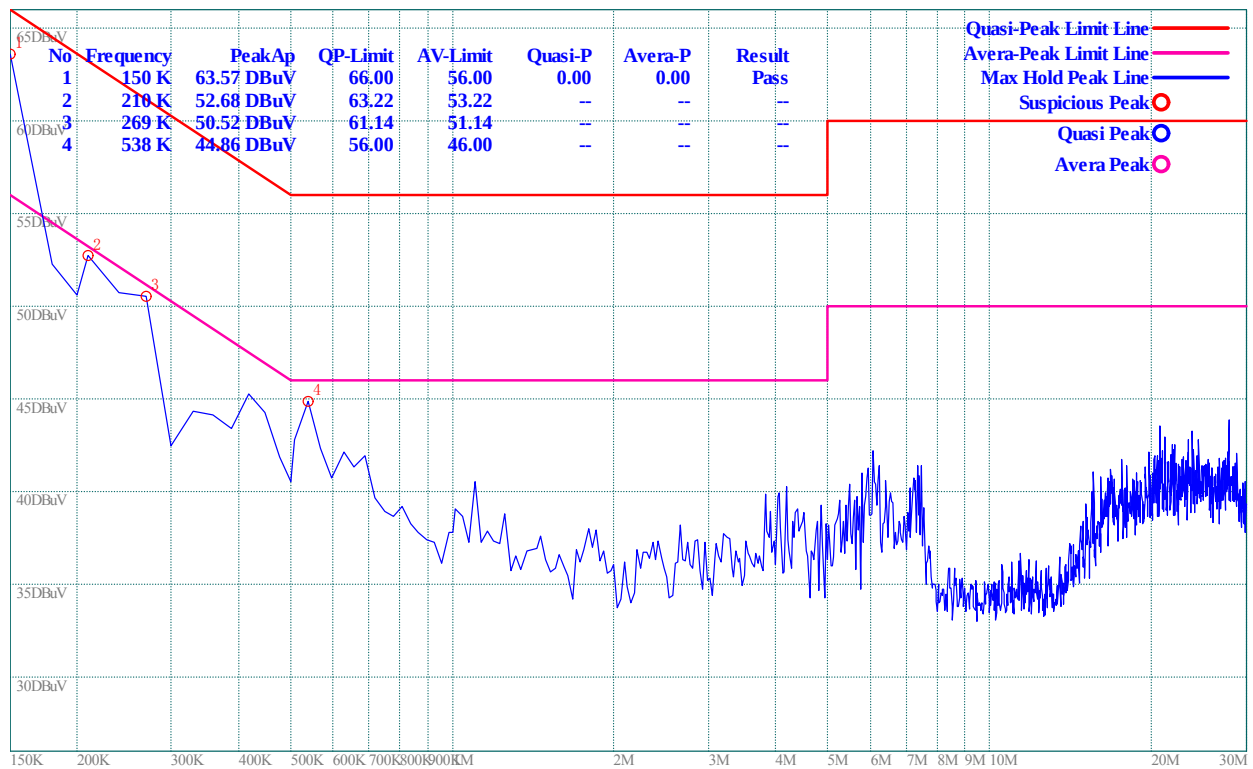
See section 2.2.1 of this report.

3.1.3 Test Result

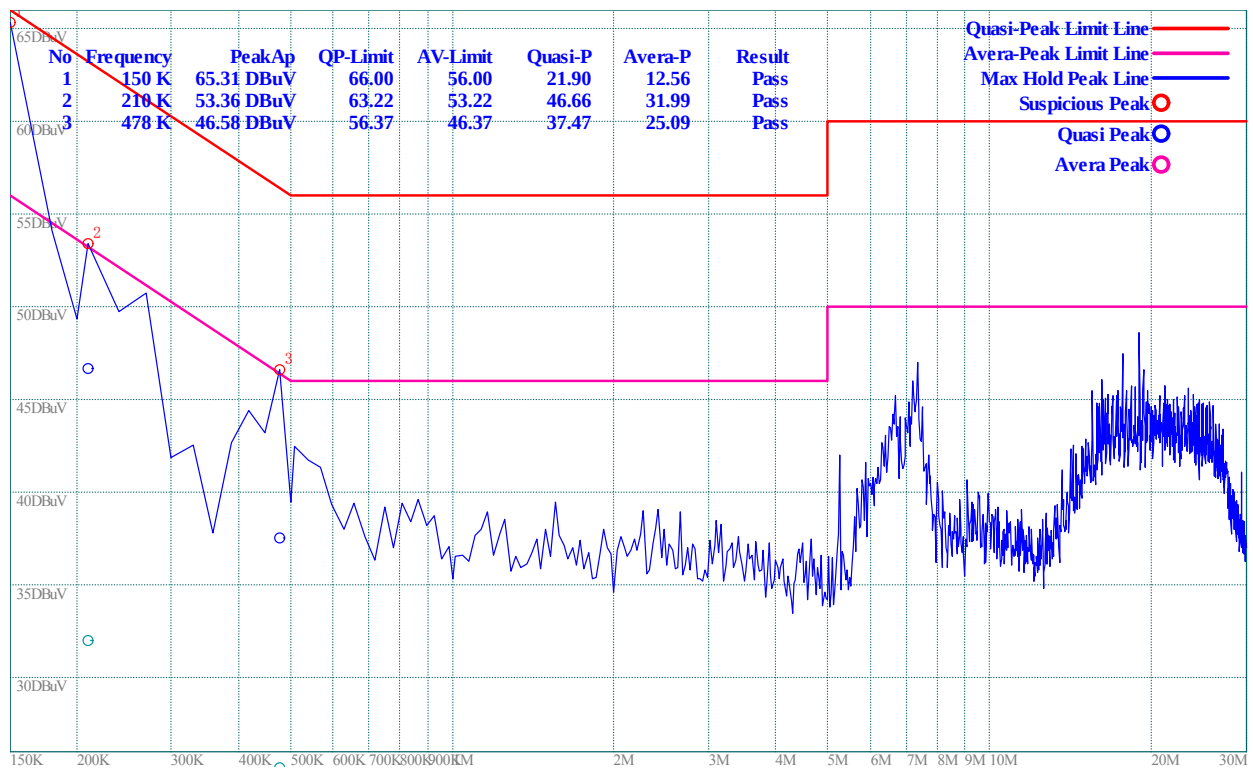
The maximum conducted interference is searched using Peak (PK), Quasi-peak (QP) and Average (AV) detectors; the emission levels more than the AV and QP limits, and that have narrow margins from the AV and QP limits will be re-measured with AV and QP detectors. Tests for both L phase and N phase lines of the power mains connected to the EUT are performed. All test modes are considered, refer to recorded points and plots below.

3.1.3.1 Test Mode

A. Test Plot and Suspicious Points:



(Plot A: L Phase)



(Plot B: N Phase)

Test Result :PASS

3.2 Radiated Emission

3.2.1 Requirement

According to FCC section 15.109, the field strength of radiated emissions from unintentional radiators at a distance of 3 meters shall not exceed the following values:

Frequency range (MHz)	Field Strength	
	$\mu\text{V/m}$	$\text{dB}\mu\text{V/m}$
30 - 88	100	40
88 - 216	150	43.5
216 - 960	200	46
Above 960	500	54

NOTE:

- a) Field Strength ($\text{dB}\mu\text{V/m}$) = $20 \cdot \log[\text{Field Strength } (\mu\text{V/m})]$.
- b) In the emission tables above, the tighter limit applies at the band edges.

3.2.2 Test Description

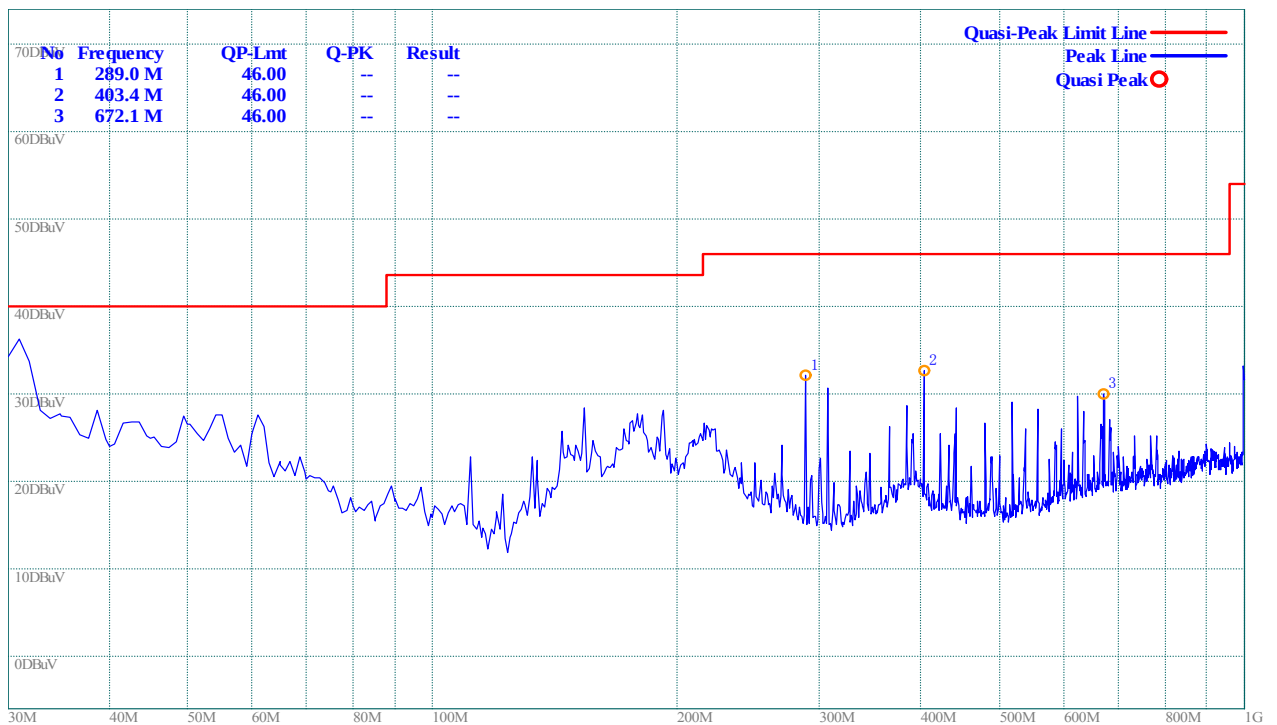
See section 2.2.2 of this report.

3.2.3 Test Result

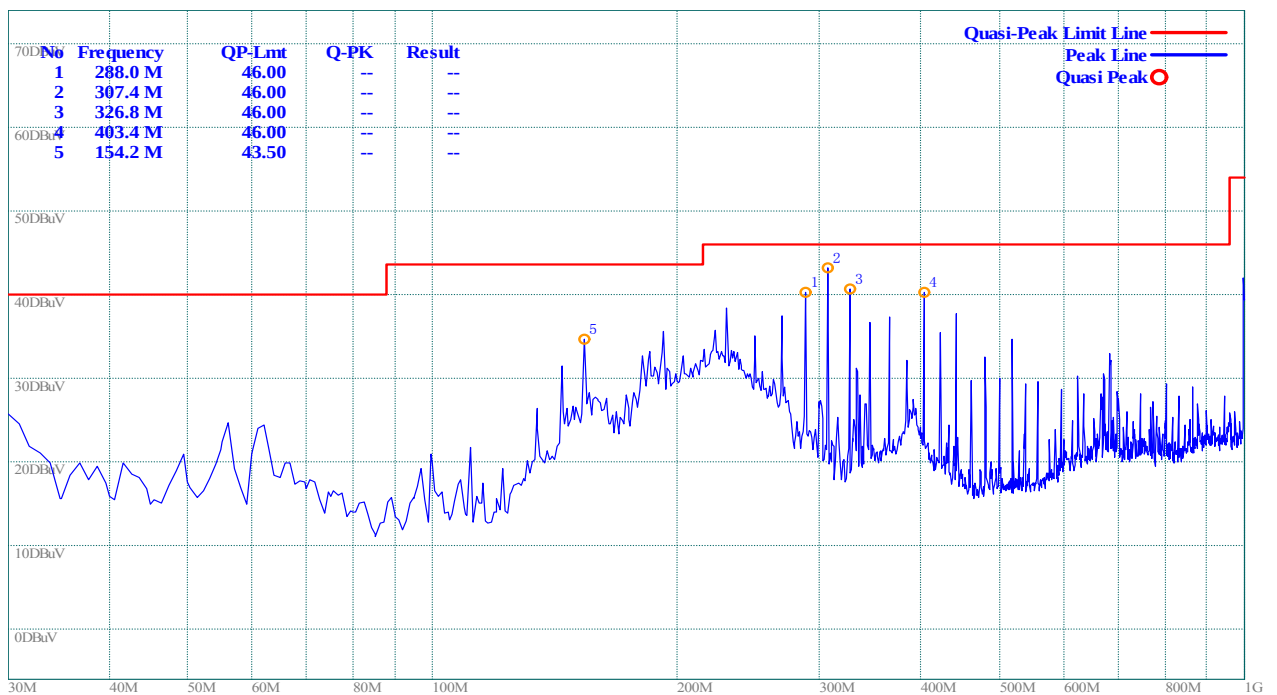
The maximum radiated emission is searched using PK, QP and AV detectors; the emission levels more than the limits, and that have narrow margins from the limits will be re-measured with AV and QP detectors. Both the vertical and the horizontal polarizations of the Test Antenna are considered to perform the tests. All test modes are considered, refer to recorded points and plots below.

3.2.3.1 Test Mode

A. Test Plots and Suspicious Points:



(Plot A: Test Antenna Vertical)



(Plot B: Test Antenna Horizontal)

Test Result :PASS

**** END OF REPORT ****